



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Norbert Marxer et al.  
Assignee: KLA-Tencor Corporaiton  
Title: PROCESS AND ASSEMBLY FOR NON-DESTRUCTIVE SURFACE  
INSPECTIONS  
Application No.: 10/619,109 Filing Date: July 10, 2003  
Examiner: Richard A. Rosenberger Group Art Unit: 2877  
Docket No.: TNCR.007US3 Conf. No.: 5810

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Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**INFORMATION DISCLOSURE STATEMENT**

Dear Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicant(s) call(s) the documents listed on the enclosed Form PTO-1449 to the Examiner's attention in this patent application.

This application has a filing date after June 30, 2003. Copies of the U.S. Patent(s) and U.S. Published Patent Application(s) documents listed on the accompanying Form PTO-1449 are not enclosed.

Copies of the documents listed on the accompanying Form PTO-1449 that are not enclosed were previously submitted in Application(s) No. 08/216,834 and 08/533,632, and U.S. Patent No. 6,271,916, issued August 7, 2001, and U.S. Patent No. 6,606,153, issued August 12, 2003 from which this Application claims an earlier effective filing date.

Citation of these documents shall not be construed as (1) an admission that the documents are prior art with respect to the invention or inventions claimed in this application, (2) a

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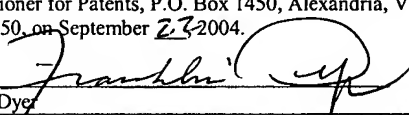
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Attorney Docket No.: TNCR.210US1

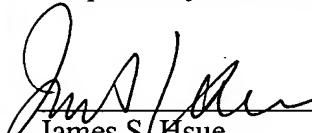
Application No.: 10/678,920

representation that a search has been made (other than as indicated by any cited document), or  
(3) an admission that the cited information is, or is considered to be, material to patentability as  
defined in § 1.56(b).

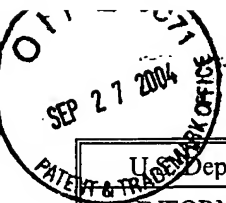
This information disclosure statement is submitted under 37 C.F.R. § 1.97(c). A check  
including \$180.00 for the information disclosure statement fee under 37 C.F.R. § 1.17(p), is  
enclosed. The Commissioner is authorized, however, to charge any fee that may be required, or  
to credit any overpayment, against Deposit Account No. 502664. This form is being submitted  
in duplicate.

<p><u>Certificate of Mailing Under 37 CFR 1.8</u></p> <p>I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope address to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on September <u>23</u> 2004.</p> <p> Franklin Dyer</p>
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Respectfully submitted,

  
James S. Hsue  
Reg. No. 29,545

9/22/04  
Date



U.S. Department of Commerce, Patent and Trademark INFORMATION DISCLOSURE STATEMENT BY APPLICANT	Atty. Docket No. TNCR.007US3	Application No. 10/619,109
(Use several sheets if necessary)	Applicant(s) Norbert Marxer et al.	Conf. No. 5810
	Filing Date July 10, 2003	Group 2877

## U.S. Patent Documents

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	1	4,314,763	Feb., 1982	Steigmeier et al.			
	2	4,360,275	Nov., 1982	Louderbeck			
	3	4,378,159	Mar., 1983	Galbraith.			
	4	4,391,524	Jul., 1983	Steigmeier et al.			
	5	4,423,331	Dec., 1983	Koizumi et al.			
	6	4,479,714	Oct., 1984	Lehrer			
	7	4,508,450	Apr., 1985	Ohshima et al.			
	8	4,523,841	Jun., 1985	Brunsting et al.			
	9	4,526,468	Jul., 1985	Steigmeier et al.			
	10	4,598,997	Jul., 1986	Steigmeier et al.			

## U.S. Published Patent Application Documents

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate

## Foreign Patent Documents

							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
	11	614830	Jan., 1988	JP.			Abstract	
	12	6340904	Jun., 1988	JP.			Abstract	
	13	62-85449	Nov., 1988	JP.			Abstract	

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	16	"Requirements for Future Surface Inspection Equipment for Bare Silicon Surfaces," P. Wagner and M Brohl, Wacker-Chemitronic GmbH, Burghausen, Germany, W. Baylies, BayTech Group, Weston Massachusetts.
	15	"The Importance of Media Refractive Index in Evaluating Liquid and Surface Microcontamination Measurements," R. Knollenberg et al., The Journal of Environmental Sciences, Mar./Apr. 1987.
	16	International Search Report Issued by the International Patent Office (WIPO) corresponding to the International Patent Application No.: PCT/US96/15354 issued on December 27, 1996.

Examiner

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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

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## U.S. Patent Documents

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	17	4,735,504	Apr., 1988	Tycko.			
	18	4,744,663	May., 1988	Hamashima et al.			
	19	4,893,932	Jan., 1990	Knollenberg.			
	20	5,076,692	Dec., 1991	Neukermans et al.			
	21	5,108,176	Apr., 1992	Malin et al.			
	22	5,189,481	Feb., 1993	Jann et al.			
	23	5,270,794	Dec., 1993	Tsuji et al.			
	24	5,315,609	May., 1994	Tanaka et al.			
	25	5,377,001	Dec., 1994	Malin et al.			
	26	5,377,002	Dec., 1994	Malin et al.			
	27	5,389,794	Feb., 1995	Allen et al.			
	28	5,406,367	Apr., 1995	Sopori.			
	29	6,178,257	Jan., 2001	Alumot et al.			

## U.S. Published Patent Application Documents

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate

## Foreign Patent Documents

							Translation	
		Document	Date	Country	Class	Subclass	Yes	No

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